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Edited by Rosario A. Gerhardt, Andrew P. Washabaugh, M.A. Alim and Gyeong Man Choi

Index

[More information](#)

AUTHOR INDEX

- Ahrenkiel, Richard K., 201
 Alavi, Ali, 161
 Aliev, Fouad M., 321
 Arenas, Claudio, 313
 Avdelidis, Nicolas P., 39

 Bai, Xuewen, 237
 Barbolla, J., 185, 231
 Bert, N.A., 269
 Bonnell, Dawn A., 101
 Brunkov, P.N., 269

 Castán, H., 185, 231
 Chaldyshev, V.V., 269
 Chen, G., 167
 Chernigovskii, A.V., 269
 Chiang, C.K., 197
 Chiteme, C., 45, 57
 Choi, Gyeong Man, 63
 Chung, D.D.L., 33
 Craven, Alan J., 161
 Cwilich, Gabriel, 119

 Dittrich, Thomas, 251
 Dresselhaus, Mildred S., 339
 Druz, B., 219
 Dueñas, S., 185, 231

 Eagan, Margaret, 307
 Endo, Morinobu, 339
 Enoki, Toshiaki, 347

 Finnis, Michael W., 161
 Fonseca, Fábio C., 75
 Fountzoulas, Costas G., 21

 Gerhardt, Rosario A., 289, 301, 333
 Glatz-Reichenbach, Joachim, 83
 Golecki, Ilan, 307
 González-Díaz, G., 231
 Guerrero, Victor H., 33
 Gutiérrez-Amador, M.P., 15

 Han, Jeong-In, 191
 Hao, W., 167
 Haslam, Jeffery J., 295

 Heiss, W.D., 45
 Hong, Sung-Jei, 191
 Hruskovic, Miloslav, 95

 Iijima, Sumio, 347
 Iwamoto, Mitsumasa, 225

 Johnson, David L., 295

 Kalinin, Sergei V., 101
 Kamiko, Masao, 283
 Kek, Darja, 173
 Kim, Joon Hee, 63
 Kim, Won-Keun, 191
 Kim, Yong-Hoon, 191
 Kim, Yoonho, 27
 Koch, Frederick, 251
 Kohyama, Masanori, 283
 Kola, R.R., 185
 Konnikov, S.G., 269
 Konstantinova, Elisaveta, 251
 Kordesch, Martin E., 213, 237
 Kotru, S., 243
 Kouloumbi, Niki, 39
 Kowalik, Daniel P., 33
 Kremer, German, 313
 Kwak, Min-Gi, 191
 Kytin, Vladimir, 251

 Laboy, Celestina, 289
 Lanyi, Stefan, 95
 Lappalainen, Jyrki, 173
 Lee, Chan-Jae, 191
 Lee, Kun-Hong, 151
 Li, C., 167
 Liu, Lequn, 207
 Loginenko, Oleg, 251
 Lojek, B., 201
 Lu, Guang-Hong, 283
 Lyding, Joseph W., 207

 Maier, Joachim, 3
 Majima, Yutaka, 113, 225
 Makram, Tariq, 301
 Marioli-Riga, Zaira P., 39
 Mártíl, I., 231

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Edited by Rosario A. Gerhardt, Andrew P. Washabaugh, M.A. Alim and Gyeong Man Choi

Index

[More information](#)

- Masuda, Tomohiko, 225
 Mayhall, David J., 295
 McComb, David W., 161
 McCoy, Jonathan, 107
 McLachlan, D.S., 45, 57, 69
 Meng, X., 167
 Mierisch, A.M., 137
 Moraga, Luis, 313
 Moropoulou, Antonia, 39
 Moskalenko, A., 269
 Muccillo, Eliana N.S., 75
 Muccillo, R., 75
 Munoz, Raúl C., 313

 Nagano, Kouhei, 113
 Nakazawa, Tatsuo, 339

 Oga, Meigo, 347
 Ohki, Yoshimasa, 347
 Okuda, Atsushi, 113, 225
 Osawa, Kozo, 339
 Oshida, Kyoich, 339
 Ostanin, Sergei, 161
 Otto, Jens W., 277
 Ou, Runqing, 333

 Pandey, R.K., 243
 Pantazopoulou, Paraskevi, 39
 Park, Jae-Gwan, 27
 Park, Jae-Hwan, 27
 Park, Sung-Kyu, 191
 Park, Young Min, 63
 Paxton, Anthony T., 161
 Peckerar, Martin, 107
 Pego, Robert, 107
 Perjeru, Florentina, 213, 237
 Pinkos, Kimberly, 289
 Polyakov, V.I., 219
 Porteanu, Horia-Eugen, 251
 Pothireddy, A., 277
 Prasad, Kanti, 257
 Preobrazhenskii, V.V., 269
 Putyato, M.A., 269

 Rossukanyi, N.M., 219

 Rous, Philip J., 107
 Rukovishnokov, A.I., 219

 Sakai, Wataru, 197
 Samuels, Robert J., 333
 Sato, Hirohiko, 347
 Sauti, G., 69
 Schwartz, Adam J., 295
 Semyagin, B.R., 269
 Simons, E.A., 277
 Song, Hyun-Kon, 151
 Stanishevsky, Andrei, 107
 Strümpfer, Ralf, 83
 Suenaga, Kazutomo, 347
 Sullivan, P.A., 185
 Surthi, S.R., 243

 Takai, Kazuyuki, 347
 Tamura, Tomoyuki, 283
 Taomoto, Akira, 347
 Taylor, S.R., 137
 Timoshenko, Victor, 251
 Tuller, Harry L., 173

 Uehara, Setsuri, 225

 Valenzuela, Raul, 15, 127
 Vassiliou, John K., 277
 Vidal, Guillermo, 313
 Vlachos, Dimitris, 161

 Wall, Mark A., 295
 Wang, Shoukai, 33
 Williams, Ellen D., 107
 Woodin, R.L., 213
 Wu, Junjie, 45

 Xu, W., 167

 Yamamoto, Ryoichi, 283
 Yongsunthon, Ruchirej, 107
 Yu, Jixin, 207

 Zou, Xiaodong, 301
 Zypman, Fredy R., 119

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978-1-107-41202-6 - Electrically Based Microstructural Characterization III

Edited by Rosario A. Gerhardt, Andrew P. Washabaugh, M.A. Alim and Gyeong Man Choi

Index

[More information](#)

SUBJECT INDEX

- ab initio method, 283
- aircraft panels, 39
- Al grain boundary, 283
- bricklayer model, 3
- buffer, 197
- bulk ferroelectrics, 21
- capacitance-voltage characteristics, 269
- carbon nanotubes, 101
- cathode material, 167
- cellular systems, 57
- cerium oxide, 173
- charge-discharge capacity, 339
- charged-based, 219
- CoFeBSi amorphous wires, 127
- composite(s), 33, 63
 - patching, 39
- conducting composites, 83
- Coulomb blockade, 113
- critical exponent, 45
- current
 - crowding, 107
 - limiting, 83
- damage diagnostic, 201
- deep level, 219
 - transient spectroscopy, 213, 237
- dichroic ratio, 333
- dielectric, 197
 - spectroscopy, 321
- diffusion, 75
- DIGS profiles from conductance
 - transients, 231
- disordered
 - carbon, 347
 - systems, 119
- displacement current, 113, 225
- dopant profiling, 207
- ECR-CVD, 231
- effective media theories, 69
- electrical
 - conduction, 3
 - resistivity, 33, 307
- electroactive interfaces, 101
- electrochemical impedance
 - spectroscopy, 151
- electromigration, 107
- electron energy-loss spectroscopy, 161
- electronic structure, 161
- equivalent circuit, 185
- exposure time, 301
- ferrites, 127
- ferroelectric memory, 243
- field effect transistor, 243
- flat-band condition, 225
- FT-IR spectra, 167
- gamma prime precipitate population, 301
- gem equation, 45
- glass-like behavior, 321
- gold film, 313
- grain size distribution, 15
- hardness indentation, 289
- high pressure, 277
- 4H-SiC, 213
- impedance spectroscopy, 15, 69, 75, 127, 173, 289
- impurity segregation, 283
- indium phosphide, 231
- ion(-)
 - beam enhanced physical vapor deposition, 307
 - implantation, 201
- iridium, 307
- lateral resolution, 95
- LEIM/S, 137
- Li(Al_xCo_{1-x})O₂, 167
- Li ion secondary battery, 339
- liquid crystal, 321
- local electrochemical impedance, 137
- LT GaAs, 269
- magnetic force microscopy, 107

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Edited by Rosario A. Gerhardt, Andrew P. Washabaugh, M.A. Alim and Gyeong Man Choi

Index

[More information](#)

- magnetoresistance, 251
- microstructural, 21
- microwave transient
 - photoconductivity, 251
- mixed conductor, 63
- modeling, 295
- MOS device, 173
- nano-crystals, 3
- nanoscale clusters, 269
- nickel base superalloy, 289
- Ni-Zn ferrites, 15
- 1/f noise, 57
- nondestructive inspection, 39
- organic coating, 137
- percolation, 45, 57
- photon localization, 119
- PLD, 243
- plutonium, 295
- polymer, 33
- polyparaphenylene, 339
- porosimetry, 151
- porous, 151
 - silicon, 251
 - TiO₂ anatase, 251
- properties, 21
- PTC-effect, 83
- pulse laser deposition, 347
- Rayleigh, 119
- relaxation, librational mode, 321
- reliability-enhancement of GaAs, 257
- resistivity, 277, 295
- RF-impedance analysis, 185
- rhodium, 307
- scaling effects, 277
- scanning
 - capacitance microscopy, 95
 - impedance microscopy, 101
- ScN, 237
- sensitivity, 95
- silicon, 201, 207, 307
- STM, 207
- stress, 307
- stretched polyaniline, 333
- surface
 - resistivity, 313
 - roughness, 313
 - space charge, 225
- tantalum pentoxide, 185
- Ta₂O₅, 191
- TFD, 191
- thin film, 197
- three-dimensional conductivity, 333
- transient spectroscopy, 219
- transport measurement, 347
- tunneling current, 113
- Waspaloy, 301
- yttria stabilized zirconia, 69
- zirconia, 63, 161
- zirconium oxide, 75